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**PATENT** 

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Patent Application of: Luca PUSTERLA et al.

Conf. No.:

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6023-169US

(BX2453M)

Title: METHOD FOR MEASURING THE

CONCENTRATION OF IMPURITIES

IN HELIUM BY ION MOBILITY

**SPECTROMETRY** 

## PRELIMINARY AMENDMENT

Simultaneously with the filing of the above-identified application with which this Preliminary Amendment is being filed, and prior to the calculation of the filing fee, Applicant hereby amends the application as follows, without prejudice:

## **Specification and Claim Amendments**

Please amend the specification and claims as follows:

Please replace the specification and claims with the Substitute Specification and claims attached hereto. A marked-up copy of the specification and claims is also attached showing underlined additions and stricken deletions.